

Amendment to the Abstract

Please amend the abstract as shown below with eliminated text shown with strike through and added text underlined.

~~System~~ A system and method for measurement of optical parameters and characterization of multiport optical devices ~~constituted by~~ incorporates ~~process control systems,~~ one or more sources of an optical test signal (11) (such as a tunable laser source), and at least one optical circuit including optical fiber and ~~several~~ other optical components arranged ~~so as to constitute an~~ interferometer. ~~interferometric optical arrangement, optical connectors, optoelectronic interfaces, photodetectors~~ Photodetectors, ~~analogical~~ analog electronic; circuits, digital electronic circuits for digital signal processing and electronic circuits for data acquisition are connected to the interferometer. ~~, the test~~ Test and reference optical signals ~~traversing~~ traverse paths ~~with any~~ having lengths, that can be identical or distinct, ~~the optical signal traversing at~~ with at least one of ~~said~~ the paths of the interferometer being phase- and/or frequency-modulated. The signals of both interferometer arms are summed at a ~~same~~ photodetector (26) that translates to the electric domain the heterodyning of the ~~optic~~ optical signals, which contain the information of the optical characteristics of the device under test (DUT) (17). ~~(device under test), the~~ The transfer function of the optical signals between the diverse ports of the DUT ~~being~~ is described by means of the optical "S"-Parameters where each "S_{xy}" parameter is represented using the formalism of Jones (Jones matrix) and/or the formalism of Muller (Muller matrix) and where all the determinations of the optical characteristics of the DUT (17) (~~bandwidth, phase, time delay, chromatic dispersion, 2nd order chromatic dispersion, reflectance, reflection coefficient, transmittance of the port "y" to the port "x" and vice versa, transmission coefficient of the port "y" to the port "x" and vice versa, insertion loss, polarization dependent loss, polarization mode dispersion (DGD/PMD), 2nd order DGD, etc.)~~) are based on said "S_{xy}" parameters.